



Application of X-ray Computed Tomography

Guest Editors:

Prof. Dr. Risco Ramon

Department of Applied Physics,
University of Seville, 41004
Seville, Spain

Dr. Jing Qu

Advanced Materials
Characterization Laboratory,
University of Delaware, Newark,
DE 19716, USA

Deadline for manuscript
submissions:

closed (20 August 2023)

Message from the Guest Editors

Dear Colleagues,

We are inviting submissions to this Special Issue on the “Application of X-ray Computed Tomography”.

X-ray computed tomography is a widespread analysis technique. The spectrum of its applications ranges from medicine to metallurgy, microelectronics, geoscience, material science, engineering, 3D printing, etc. Its very high spatial and temporal resolution, together with its non-invasive character, makes X-ray computed tomography the best option of analysis in many cases.

In this Special Issue, we invite authors to present their latest cutting-edge research in the field.

Prof. Dr. Risco Ramon

Dr. Jing Qu

Guest Editors





an Open Access Journal by MDPI

Editor-in-Chief

Prof. Dr. Giulio Nicola Cerullo

Dipartimento di Fisica,
Politecnico di Milano, Piazza L.
da Vinci 32, 20133 Milano, Italy

Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Author Benefits

Open Access: free for readers, with article processing charges (APC) paid by authors or their institutions.

High Visibility: indexed within Scopus, SCIE (Web of Science), Inspec, CAPus / SciFinder, and other databases.

Journal Rank: JCR - Q2 (*Engineering, Multidisciplinary*) / CiteScore - Q1 (*General Engineering*)

Contact Us

Applied Sciences Editorial Office
MDPI, St. Alban-Anlage 66
4052 Basel, Switzerland

Tel: +41 61 683 77 34
www.mdpi.com

mdpi.com/journal/applsci
applsci@mdpi.com
X@Applsci